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MAGNETIC SUSCEPTIBILITY OF $Sn_{1-x}Eu_xTe^*$

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The magnetic susceptibility of Bridgman-grown $Sn_{1-x}Eu_x$ Te with nominal values of x up to 0.095 was measured over a temperature range from 2 to 385 K. The samples were p-type with hole concentrations up to 1.5×10^{21} cm⁻³. The susceptibility data above 50 K followed the Curie-Weiss relation with a small Curie temperature. At about 10 K a small cusp in susceptibility was observed in samples with the higher range of x values. The data indicate a presence of both antiferromagnetic and ferromagnetic exchange interactions, with some paramagnetic contributions from charged defects. There is also evidence of Eu going into the lattice both as Eu^{2+} and Eu^{3+} ions.

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1. Introduction

Magnetic properties of rare-earth-doped IV-VI chalcogenides have been studied recently in $Pb_{1-x}Gd_xTe$, $Pb_{1-x}Eu_xTe$, and $Sn_{1-x}Gd_xTe$ [1-3]. The results showed a very weak antiferromagnetic exchange coupling among magnetic ions, with no evidence of RKKY-type ferromagnetic interaction observed in $Pb_{1-x-y}Sn_yMn_xTe$ [4]. The susceptibility measurements of $Sn_{1-x}Eu_xTe$ by Mathur et al. at temperatures up to 70 K showed a deviation from the Curie-Weiss behavior similar to that in spin-glass materials [5]. Here we are reporting results on $Sn_{1-x}Eu_xTe$ at temperatures up to 385 K.

2. Experiment

The samples of $Sn_{1-x}Eu_x$ Te were cut from boules grown by the Bridgman technique. The x_v values determined by electron microprobe analysis and the hole concentrations at 4.2 K (both with an accuracy of about 20%, including variation throughout the sample) are given in Table.

The magnetic susceptibility was measured using a SQUID detection system at temperatures from 2 to 385 K and at magnetic fields from 5 to 500 Oe. The SnTe host diamagnetic susceptibility was measured from 2 to 375 K at fields from 0.5 to 5 kOe. The experimental method and details were described previously [2, 3].

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trations.				
Sample	x_v	$ar{x}$	θ [K]	$p \ [10^{21} \ \mathrm{cm^{-3}}]$
A	0.095	0.020	0.706	1.04
B	0.085	0.025	-1.879	1.11
С	0.065	0.014	0.678	1.14
D	0.045	0.009	0.373	1.49

TABLE Susceptibility fitting parameters and carrier concentrations.

3. Results and discussion

The susceptibility data were fitted over the temperature range from 50 to 385 K to the Curie-Weiss law

$$\chi = \frac{P_1}{T+\theta} + \chi_0,$$

where T is the absolute temperature, P_1 is the Curie constant, θ is the Curie temperature, and χ_0 is the diamagnetic susceptibility of the host lattice. P_1 and θ were fitting parameters, χ_0 was taken from experimental measurements of SnTe and varied linearly from -4.7×10^{-7} emu/g at 50 K to -3.3×10^{-7} emu/g at 375 K. The effective content of Eu ions, \bar{x} , was determined from P_1 as described in Ref. [3], with estimated error of 20%.



Fig. 1. Inverse susceptibility vs. temperature for $Sn_{1-x}Eu_xTe$. Solid lines are fits to the Curie-Weiss law.

The experimental results and fits are shown in Fig. 1. The fitting parameters are given in Table.

There is a large difference between the x_v and \bar{x} parameters. The value $x_v - \bar{x}$ increases with increasing Eu content, followed by a decrease in p. It is

possible that the susceptibility measurements give the number of Eu^{2+} ions with a spin 3.5, while a large part of Eu enters the lattice as Eu^{3+} ions, with no magnetic moment at the ground state, and compensates the *p*-type material.

The Curie temperature, θ , is very small, may be regarded as zero within our experimental accuracy. Therefore, we did not estimate the exchange parameter values from θ .

It was impossible to obtain good fits to the experimental data using a constant diamagnetic susceptibility of SnTe. Therefore, for χ_0 we used the exact values obtained from experiment, where χ_0 varied linearly with T. This approach gave very good fits, as is seen in Fig. 1.

In Fig. 2 we show the magnetic susceptibility vs. temperature at temperatures below 50 K. At about 10 K there is a cusp in the susceptibility of samples



Fig. 2. Magnetic susceptibility vs. temperature for $Sn_{1-x}Eu_xTe$. The lines represent the experimental data.

with $x_v \ge 0.085$ and a faint trace of that cusp in the sample with $x_v = 0.065$. That effect, together with the Curie temperature close to zero, indicates a transition to a spin-glass phase, due to antiferromagnetic coupling between Eu ions and ferromagnetic coupling related either to more distant neighbors or carrier-induced RKKY-type interaction, as in $Pb_{1-x-y}Sn_yMn_xTe$ [4].

The subsequent increase in susceptibility below 5 K may be due to other than Eu paramagnetic impurities or defects. We observed previously similar effect in *p*-type PbTe [6], explained by Pankratov as related to the magnetic moment of charged nonstoichiometric defects [7].

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